

**Search Notes**

Application/Control No.

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Examiner

Wenpeng Chen

Applicant(s)/Patent under  
Reexamination

RITTER ET AL.

Art Unit

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**SEARCHED**

Class	Subclass	Date	Examiner

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST (USPAT, US-PUPUB, EPO, JPO, DERWENT, IBM_TDB, USOCR, FPRS) - See search history printout.	10/4/06	me
IEEE Xplore - See search condition and result printout.	10/18/06	me